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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	768
Total RAM Bits	-
Number of I/O	81
Number of Gates	30000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	132-WFQFN
Supplier Device Package	132-QFN (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/agl030v2-qng132i

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Table 2-3 • Flash Programming Limits – Retention, Storage, and Operating Temperature¹

Product Grade	Programming Cycles	Program Retention (biased/unbiased)	Maximum Storage Temperature T _{STG} (°C) ²	Maximum Operating Junction Temperature T _J (°C) ²
Commercial	500	20 years	110	100
Industrial	500	20 years	110	100

- 1. This is a stress rating only; functional operation at any condition other than those indicated is not implied.
- These limits apply for program/data retention only. Refer to Table 2-1 on page 2-1 and Table 2-2 on page 2-2 for device operating conditions and absolute limits.

Table 2-4 • Overshoot and Undershoot Limits 1

VCCI	Average VCCI–GND Overshoot or Undershoot Duration as a Percentage of Clock Cycle ²	Maximum Overshoot/ Undershoot ²
2.7 V or less	10%	1.4 V
	5%	1.49 V
3 V	10%	1.1 V
	5%	1.19 V
3.3 V	10%	0.79 V
	5%	0.88 V
3.6 V	10%	0.45 V
	5%	0.54 V

Notes:

- 1. Based on reliability requirements at junction temperature at 85°C.
- 2. The duration is allowed at one out of six clock cycles. If the overshoot/undershoot occurs at one out of two cycles, the maximum overshoot/undershoot has to be reduced by 0.15 V.
- 3. This table does not provide PCI overshoot/undershoot limits.

I/O Power-Up and Supply Voltage Thresholds for Power-On Reset (Commercial and Industrial)

Sophisticated power-up management circuitry is designed into every IGLOO device. These circuits ensure easy transition from the powered-off state to the powered-up state of the device. The many different supplies can power up in any sequence with minimized current spikes or surges. In addition, the I/O will be in a known state through the power-up sequence. The basic principle is shown in Figure 2-1 on page 2-4 and Figure 2-2 on page 2-5.

There are five regions to consider during power-up.

IGLOO I/Os are activated only if ALL of the following three conditions are met:

- 1. VCC and VCCI are above the minimum specified trip points (Figure 2-1 on page 2-4 and Figure 2-2 on page 2-5).
- 2. VCCI > VCC 0.75 V (typical)
- 3. Chip is in the operating mode.

VCCI Trip Point:

Ramping up (V5 devices): 0.6 V < trip_point_up < 1.2 V Ramping down (V5 Devices): 0.5 V < trip_point_down < 1.1 V Ramping up (V2 devices): 0.75 V < trip_point_up < 1.05 V Ramping down (V2 devices): 0.65 V < trip_point_down < 0.95 V

VCC Trip Point:

Ramping up (V5 devices): 0.6 V < trip_point_up < 1.1 V Ramping down (V5 devices): 0.5 V < trip_point_down < 1.0 V

Table 2-64 • Minimum and Maximum DC Input and Output Levels for LVCMOS 3.3 V Wide Range Applicable to Standard Plus I/O Banks

3.3 V LVCMO	S Wide Range	VI	L	VIH		VOL	VOH	IOL	ЮН	IOSL	IOSH	IIL ²	IIH ³
Drive Strength	Equivalent Software Default Drive Strength Option ¹	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	μΑ	μΑ	Max. mA ⁴	Max. mA ⁴	μ Α ⁵	μ Α ⁵
100 μΑ	2 mA	-0.3	0.8	2	3.6	0.2	VDD - 0.2	100	100	25	27	10	10
100 μΑ	4 mA	-0.3	0.8	2	3.6	0.2	VDD - 0.2	100	100	25	27	10	10
100 μΑ	6 mA	-0.3	0.8	2	3.6	0.2	VDD - 0.2	100	100	51	54	10	10
100 μΑ	8 mA	-0.3	0.8	2	3.6	0.2	VDD - 0.2	100	100	51	54	10	10
100 μΑ	12 mA	-0.3	0.8	2	3.6	0.2	VDD - 0.2	100	100	103	109	10	10
100 μΑ	16 mA	-0.3	0.8	2	3.6	0.2	VDD – 0.2	100	100	103	109	10	10

- 1. The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is \pm 100 μ A. Drive strengths displayed in software are supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
- 2. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 3. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 4. Currents are measured at 100°C junction temperature and maximum voltage.
- 5. Currents are measured at 85°C junction temperature.
- 6. Software default selection highlighted in gray.

Table 2-75 • 3.3 V LVCMOS Wide Range Low Slew – Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.7

Applicable to Standard Plus Banks

Drive Strength	Equivalent Software Default Drive Strength Option ¹	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{zHS}	Units
100 μΑ	2 mA	Std.	1.55	6.69	0.26	1.32	1.10	6.69	5.73	3.41	3.72	12.48	11.52	ns
100 μΑ	4 mA	Std.	1.55	6.69	0.26	1.32	1.10	6.69	5.73	3.41	3.72	12.48	11.52	ns
100 μΑ	6 mA	Std.	1.55	5.58	0.26	1.32	1.10	5.58	5.01	3.77	4.35	11.36	10.79	ns
100 μΑ	8 mA	Std.	1.55	5.58	0.26	1.32	1.10	5.58	5.01	3.77	4.35	11.36	10.79	ns
100 μΑ	12 mA	Std.	1.55	4.82	0.26	1.32	1.10	4.82	4.44	4.02	4.76	10.61	10.23	ns
100 μΑ	16 mA	Std.	1.55	4.82	0.26	1.32	1.10	4.82	4.44	4.02	4.76	10.61	10.23	ns

- 1. The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is ± 100 μA. Drive strengths displayed in software are supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
- 2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-76 • 3.3 V LVCMOS Wide Range High Slew – Applies to 1.2 V DC Core Voltage Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.7 Applicable to Standard Plus Banks

Drive Strength	Equivalent Software Default Drive Strength Option ¹	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{zHS}	Units
100 µA	2 mA	Std.	1.55	4.10	0.26	1.32	1.10	4.10	3.30	3.40	3.92	9.89	9.09	ns
100 µA	4 mA	Std.	1.55	4.10	0.26	1.32	1.10	4.10	3.30	3.40	3.92	9.89	9.09	ns
100 µA	6 mA	Std.	1.55	3.51	0.26	1.32	1.10	3.51	2.79	3.76	4.56	9.30	8.57	ns
100 µA	8 mA	Std.	1.55	3.51	0.26	1.32	1.10	3.51	2.79	3.76	4.56	9.30	8.57	ns
100 μΑ	12 mA	Std.	1.55	3.20	0.26	1.32	1.10	3.20	2.52	4.01	4.97	8.99	8.31	ns
100 µA	16 mA	Std.	1.55	3.20	0.26	1.32	1.10	3.20	2.52	4.01	4.97	8.99	8.31	ns

Notes:

- The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is ± 100 μA. Drive strengths
 displayed in software are supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
- 2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.
- 3. Software default selection highlighted in gray.

Table 2-81 • Minimum and Maximum DC Input and Output Levels
Applicable to Standard I/O Banks

2.5 V LVCMOS	VIL		VIH		VOL	VOH	IOL	ЮН	IOSH	IOSL	IIL ¹	IIH ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μA ⁴	μ Α ⁴
2 mA	-0.3	0.7	1.7	3.6	0.7	1.7	2	2	16	18	10	10
4 mA	-0.3	0.7	1.7	3.6	0.7	1.7	4	4	16	18	10	10
6 mA	-0.3	0.7	1.7	3.6	0.7	1.7	6	6	32	37	10	10
8 mA	-0.3	0.7	1.7	3.6	0.7	1.7	8	8	32	37	10	10

- 1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

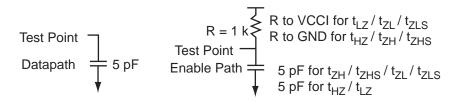


Figure 2-8 • AC Loading

Table 2-82 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	C _{LOAD} (pF)
0	2.5	1.2	5

Note: *Measuring point = Vtrip. See Table 2-29 on page 2-28 for a complete table of trip points.

2-56 Revision 27

1.2 V LVCMOS (JESD8-12A)

Low-Voltage CMOS for 1.2 V complies with the LVCMOS standard JESD8-12A for general purpose 1.2 V applications. It uses a 1.2 V input buffer and a push-pull output buffer. Furthermore, all LVCMOS 1.2 V software macros comply with LVCMOS 1.2 V wide range as specified in the JESD8-12A specification.

Table 2-127 • Minimum and Maximum DC Input and Output Levels
Applicable to Advanced I/O Banks

1.2 V LVCMOS	VIL VIH			VOL	VOH	IOL	ЮН	IOSH	IOSL	IIL ¹	IIH ²	
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μ Α ⁴	μ Α ⁴
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.26	0.25 * VCCI	0.75 * VCCI	2	2	20	26	10	10

Notes:

- 1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

Table 2-128 • Minimum and Maximum DC Input and Output Levels
Applicable to Standard Plus I/O Banks

1.2 V LVCMOS		VIL	VIH	VIH		VOH I _O		ЮН	IOSH	IOSL	IIL ¹	IIH ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μ Α ⁴	μ Α ⁴
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.26	0.25 * VCCI	0.75 * VCCI	2	2	20	26	10	10

Notes:

- 1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

Table 2-129 • Minimum and Maximum DC Input and Output Levels
Applicable to Standard I/O Banks

1.2 V LVCMOS		VIL VIH		VOL	VOH	VOH IOL		IOSH	IOSL	IIL ¹	IIH ²	
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μ Α ⁴	μA ⁴
1 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	1	1	20	26	10	10

Notes:

- 1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

3.3 V PCI, 3.3 V PCI-X

Peripheral Component Interface for 3.3 V standard specifies support for 33 MHz and 66 MHz PCI Bus applications.

Table 2-141 • Minimum and Maximum DC Input and Output Levels
Applicable to Advanced and Standard Plus I/Os

3.3 V PCI/PCI-X	VIL VIH				VOL	VOH	IOL	ЮН	IOSH	IOSL	IIL	IIH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
Per PCI specification					Per PC	l curves					10	10

Notes:

- 1. Currents are measured at 100°C junction temperature and maximum voltage.
- 2. Currents are measured at 85°C junction temperature.

AC loadings are defined per the PCI/PCI-X specifications for the datapath; Microsemi loadings for enable path characterization are described in Figure 2-12.

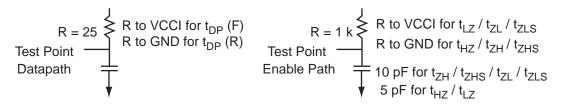


Figure 2-12 • AC Loading

AC loadings are defined per PCI/PCI-X specifications for the datapath; Microsemi loading for tristate is described in Table 2-142.

Table 2-142 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	C _{LOAD} (pF)
0	3.3	0.285 * VCCI for t _{DP(R)}	10
		0.615 * VCCI for t _{DP(F)}	

Note: *Measuring point = Vtrip. See Table 2-29 on page 2-28 for a complete table of trip points.

Timing Characteristics

1.5 V DC Core Voltage

Table 2-143 • 3.3 V PCI/PCI-X

Commercial-Case Conditions: $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V Applicable to Advanced I/O Banks

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.97	2.32	0.19	0.70	0.66	2.37	1.78	2.67	3.05	5.96	5.38	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-144 • 3.3 V PCI/PCI-X

Commercial-Case Conditions: $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V Applicable to Standard Plus I/O Banks

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.97	1.97	0.19	0.70	0.66	2.01	1.50	2.36	2.79	5.61	5.10	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-151 • Minimum and Maximum DC Input and Output Levels

DC Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
VCCI	Supply Voltage	3.0		3.3		3.6		V
VOL	Output Low Voltage	0.96	1.27	1.06	1.43	1.30	1.57	V
VOH	Output High Voltage	1.8	2.11	1.92	2.28	2.13	2.41	V
VIL, VIH	Input Low, Input High Voltages	0	3.6	0	3.6	0	3.6	V
V _{ODIFF}	Differential Output Voltage	0.625	0.97	0.625	0.97	0.625	0.97	V
V _{OCM}	Output Common-Mode Voltage	1.762	1.98	1.762	1.98	1.762	1.98	V
V _{ICM}	Input Common-Mode Voltage	1.01	2.57	1.01	2.57	1.01	2.57	V
V _{IDIFF}	Input Differential Voltage	300		300		300		mV

Table 2-152 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)
1.64	1.94	Cross point

Note: *Measuring point = Vtrip. See Table 2-28 on page 2-104 for a complete table of trip points.

Timing Characteristics

1.5 V DC Core Voltage

Table 2-153 • LVPECL – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70$ °C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V Applicable to Standard Banks

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	Units
Std.	0.97	1.67	0.19	1.16	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

1.2 V DC Core Voltage

Table 2-154 • LVPECL - Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 3.0 V Applicable to Standard Banks

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	Units
Std.	1.55	2.24	0.25	1.37	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-156 • Parameter Definition and Measuring Nodes

Parameter Name	Parameter Definition	Measuring Nodes (from, to)*
t _{OCLKQ}	Clock-to-Q of the Output Data Register	HH, DOUT
t _{OSUD}	Data Setup Time for the Output Data Register	FF, HH
t _{OHD}	Data Hold Time for the Output Data Register	FF, HH
tosuE	Enable Setup Time for the Output Data Register	GG, HH
t _{OHE}	Enable Hold Time for the Output Data Register	GG, HH
t _{OCLR2Q}	Asynchronous Clear-to-Q of the Output Data Register	LL, DOUT
tOREMCLR	Asynchronous Clear Removal Time for the Output Data Register	LL, HH
torecclr	Asynchronous Clear Recovery Time for the Output Data Register	LL, HH
t _{OECLKQ}	Clock-to-Q of the Output Enable Register	HH, EOUT
t _{OESUD}	Data Setup Time for the Output Enable Register	JJ, HH
t _{OEHD}	Data Hold Time for the Output Enable Register	JJ, HH
toesue	Enable Setup Time for the Output Enable Register	KK, HH
t _{OEHE}	Enable Hold Time for the Output Enable Register	KK, HH
t _{OECLR2Q}	Asynchronous Clear-to-Q of the Output Enable Register	II, EOUT
toeremclr	Asynchronous Clear Removal Time for the Output Enable Register	II, HH
toerecclr	Asynchronous Clear Recovery Time for the Output Enable Register	II, HH
t _{ICLKQ}	Clock-to-Q of the Input Data Register	AA, EE
t _{ISUD}	Data Setup Time for the Input Data Register	CC, AA
t _{IHD}	Data Hold Time for the Input Data Register	CC, AA
t _{ISUE}	Enable Setup Time for the Input Data Register	BB, AA
t _{IHE}	Enable Hold Time for the Input Data Register	BB, AA
t _{ICLR2Q}	Asynchronous Clear-to-Q of the Input Data Register	DD, EE
t _{IREMCLR}	Asynchronous Clear Removal Time for the Input Data Register	DD, AA
t _{IRECCLR}	Asynchronous Clear Recovery Time for the Input Data Register	DD, AA

Note: *See Figure 2-17 on page 2-86 for more information.

Table 2-183 • AGL060 Global Resource

Commercial-Case Conditions: T_J = 70°C, VCC = 1.14 V

		S	Std.		
Parameter	Description	Min. ¹	Max. ²	Units	
t _{RCKL}	Input Low Delay for Global Clock	2.04	2.33	ns	
t _{RCKH}	Input High Delay for Global Clock	2.10	2.51	ns	
t _{RCKMPWH}	Minimum Pulse Width High for Global Clock	1.40		ns	
t _{RCKMPWL}	Minimum Pulse Width Low for Global Clock	1.65		ns	
t _{RCKSW}	Maximum Skew for Global Clock		0.40	ns	

Notes:

- 1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
- 2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
- 3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-184 • AGL125 Global Resource

Commercial-Case Conditions: T_J = 70°C, VCC = 1.14 V

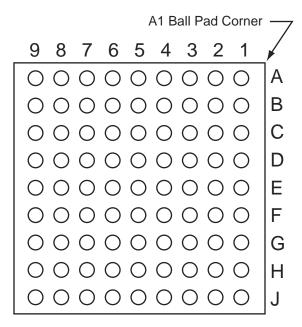
			s	td.	
Parameter	Description	-	Min. ¹	Max. ²	Units
t _{RCKL}	Input Low Delay for Global Clock		2.08	2.54	ns
t _{RCKH}	Input High Delay for Global Clock		2.15	2.77	ns
t _{RCKMPWH}	Minimum Pulse Width High for Global Clock		1.40		ns
t _{RCKMPWL}	Minimum Pulse Width Low for Global Clock		1.65		ns
t _{RCKSW}	Maximum Skew for Global Clock			0.62	ns

Notes:

- 1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
- 2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
- 3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

4 - Package Pin Assignments

UC81



Note: This is the bottom view of the package.

Note

For more information on package drawings, see PD3068: Package Mechanical Drawings.



IGLOO Low Power Flash FPGAs

	CS281		CS281		CS281
Pin Number	AGL600 Function	Pin Number	AGL600 Function	Pin Number	AGL600 Function
A1	GND	B18	VCCIB1	E13	IO46RSB0
A2	GAB0/IO02RSB0	B19	IO61NDB1	E14	GBB1/IO57RSB0
A3	GAC1/IO05RSB0	C1	GAB2/IO173PPB3	E15	IO62NPB1
A4	IO07RSB0	C2	IO174NPB3	E16	IO63PPB1
A5	IO10RSB0	C6	IO12RSB0	E18	IO64PPB1
A6	IO14RSB0	C14	IO50RSB0	E19	IO65NPB1
A7	IO18RSB0	C18	IO60NPB1	F1	IO168NPB3
A8	IO21RSB0	C19	GBB2/IO61PDB1	F2	GND
A9	IO22RSB0	D1	IO170PPB3	F3	IO169PPB3
A10	VCCIB0	D2	IO172NPB3	F4	IO170NPB3
A11	IO33RSB0	D4	GAA0/IO00RSB0	F5	IO173NPB3
A12	IO40RSB0	D5	GAA1/IO01RSB0	F15	IO63NPB1
A13	IO37RSB0	D6	IO09RSB0	F16	IO65PPB1
A14	IO48RSB0	D7	IO16RSB0	F17	IO64NPB1
A15	IO51RSB0	D8	IO19RSB0	F18	GND
A16	IO53RSB0	D9	IO26RSB0	F19	IO68PPB1
A17	GBC1/IO55RSB0	D10	GND	G1	IO167NPB3
A18	GBA0/IO58RSB0	D11	IO34RSB0	G2	IO165NDB3
A19	GND	D12	IO45RSB0	G4	IO168PPB3
B1	GAA2/IO174PPB3	D13	IO49RSB0	G5	IO167PPB3
B2	VCCIB0	D14	IO47RSB0	G7	GAC2/IO172PPB3
В3	GAB1/IO03RSB0	D15	GBB0/IO56RSB0	G8	VCCIB0
B4	GAC0/IO04RSB0	D16	GBA2/IO60PPB1	G9	IO28RSB0
B5	IO06RSB0	D18	GBC2/IO62PPB1	G10	IO32RSB0
В6	GND	D19	IO66NPB1	G11	IO43RSB0
В7	IO15RSB0	E1	IO169NPB3	G12	VCCIB0
B8	IO20RSB0	E2	IO171PPB3	G13	IO66PPB1
В9	IO23RSB0	E4	IO171NPB3	G15	IO67NDB1
B10	IO24RSB0	E5	IO08RSB0	G16	IO67PDB1
B11	IO36RSB0	E6	IO11RSB0	G18	GCC0/IO69NPB1
B12	IO35RSB0	E7	IO13RSB0	G19	GCB1/IO70PPB1
B13	IO44RSB0	E8	IO17RSB0	H1	GFB0/IO163NPB3
B14	GND	E9	IO25RSB0	H2	IO165PDB3
B15	IO52RSB0	E10	IO30RSB0	H4	GFC1/IO164PPB3
B16	GBC0/IO54RSB0	E11	IO41RSB0	H5	GFB1/IO163PPB3
B17	GBA1/IO59RSB0	E12	IO42RSB0	H7	VCCIB3



IGLOO Low Power Flash FPGAs

(QN132
Pin Number	AGL060 Function
A1	GAB2/IO00RSB1
A2	IO93RSB1
A3	VCCIB1
A4	GFC1/IO89RSB1
A5	GFB0/IO86RSB1
A6	VCCPLF
A7	GFA1/IO84RSB1
A8	GFC2/IO81RSB1
A9	IO78RSB1
A10	VCC
A11	GEB1/IO75RSB1
A12	GEA0/IO72RSB1
A13	GEC2/IO69RSB1
A14	IO65RSB1
A15	VCC
A16	IO64RSB1
A17	IO63RSB1
A18	IO62RSB1
A19	IO61RSB1
A20	IO58RSB1
A21	GDB2/IO55RSB1
A22	NC
A23	GDA2/IO54RSB1
A24	TDI
A25	TRST
A26	GDC1/IO48RSB0
A27	VCC
A28	IO47RSB0
A29	GCC2/IO46RSB0
A30	GCA2/IO44RSB0
A31	GCA0/IO43RSB0
A32	GCB1/IO40RSB0
A33	IO36RSB0
A34	VCC
A35	IO31RSB0
A36	GBA2/IO28RSB0

QN132		
Pin Number AGL060 Function		
A37	GBB1/IO25RSB0	
A38	GBC0/IO22RSB0	
A39	VCCIB0	
A40	IO21RSB0	
A41	IO18RSB0	
A42	IO15RSB0	
A43	IO14RSB0	
A44	IO11RSB0	
A45	GAB1/IO08RSB0	
A46	NC	
A47	GAB0/IO07RSB0	
A48	IO04RSB0	
B1	IO01RSB1	
B2	GAC2/IO94RSB1	
В3	GND	
B4	GFC0/IO88RSB1	
B5	VCOMPLF	
В6	GND	
B7	GFB2/IO82RSB1	
B8	IO79RSB1	
B9	GND	
B10	GEB0/IO74RSB1	
B11	VMV1	
B12	FF/GEB2/IO70RSB 1	
B13	IO67RSB1	
B14	GND	
B15	NC	
B16	NC	
B17	GND	
B18	IO59RSB1	
B19 GDC2/IO56RSB		
B20	GND	
B21	GNDQ	
B22	TMS	
B23	TDO	
	l	

QN132		
Pin Number AGL060 Funct		
B24	GDC0/IO49RSB0	
B25	GND	
B26	NC	
B27	GCB2/IO45RSB0	
B28	GND	
B29	GCB0/IO41RSB0	
B30	GCC1/IO38RSB0	
B31	GND	
B32	GBB2/IO30RSB0	
B33	VMV0	
B34	GBA0/IO26RSB0	
B35	GBC1/IO23RSB0	
B36	GND	
B37	IO20RSB0	
B38	IO17RSB0	
B39	GND	
B40	IO12RSB0	
B41	GAC0/IO09RSB0	
B42	GND	
B43	GAA1/IO06RSB0	
B44	GNDQ	
C1	GAA2/IO02RSB1	
C2	IO95RSB1	
C3	VCC	
C4	GFB1/IO87RSB1	
C5	GFA0/IO85RSB1	
C6	GFA2/IO83RSB1	
C7	IO80RSB1	
C8	VCCIB1	
C9	GEA1/IO73RSB1	
C10	GNDQ	
C11	GEA2/IO71RSB1	
C12	IO68RSB1	
C13	VCCIB1	
C14	NC	
C15	NC	



FG484		
Pin Number	AGL400 Function	
AA15	NC	
AA16	NC	
AA17	NC	
AA18	NC	
AA19	NC	
AA20	NC	
AA21	VCCIB1	
AA22	GND	
AB1	GND	
AB2	GND	
AB3	VCCIB2	
AB4	NC	
AB5	NC	
AB6	IO121RSB2	
AB7	IO119RSB2	
AB8	IO114RSB2	
AB9	IO109RSB2	
AB10	NC	
AB11	NC	
AB12	IO104RSB2	
AB13	IO103RSB2	
AB14	NC	
AB15	NC	
AB16	IO91RSB2	
AB17	IO90RSB2	
AB18	NC	
AB19	NC	
AB20	VCCIB2	
AB21	GND	
AB22	GND	
B1	GND	
B2	VCCIB3	
В3	NC	
B4	NC	
B5	NC	
В6	NC	



	FG484
Pin Number	AGL400 Function
C21	NC
C22	VCCIB1
D1	NC
D2	NC
D3	NC
D4	GND
D5	GAA0/IO00RSB0
D6	GAA1/IO01RSB0
D7	GAB0/IO02RSB0
D8	IO16RSB0
D9	IO17RSB0
D10	IO22RSB0
D11	IO28RSB0
D12	IO34RSB0
D13	IO37RSB0
D14	IO41RSB0
D15	IO43RSB0
D16	GBB1/IO57RSB0
D17	GBA0/IO58RSB0
D18	GBA1/IO59RSB0
D19	GND
D20	NC
D21	NC
D22	NC
E1	NC
E2	NC
E3	GND
E4	GAB2/IO154UDB3
E5	GAA2/IO155UDB3
E6	IO12RSB0
E7	GAB1/IO03RSB0
E8	IO13RSB0
E9	IO14RSB0
E10	IO21RSB0
E11	IO27RSB0
E12	IO32RSB0

FG484	
Pin Number	AGL1000 Function
A1	GND
A2	GND
A3	VCCIB0
A4	IO07RSB0
A5	IO09RSB0
A6	IO13RSB0
A7	IO18RSB0
A8	IO20RSB0
A9	IO26RSB0
A10	IO32RSB0
A11	IO40RSB0
A12	IO41RSB0
A13	IO53RSB0
A14	IO59RSB0
A15	IO64RSB0
A16	IO65RSB0
A17	IO67RSB0
A18	IO69RSB0
A19	NC
A20	VCCIB0
A21	GND
A22	GND
AA1	GND
AA2	VCCIB3
AA3	NC
AA4	IO181RSB2
AA5	IO178RSB2
AA6	IO175RSB2
AA7	IO169RSB2
AA8	IO166RSB2
AA9	IO160RSB2
AA10	IO152RSB2
AA11	IO146RSB2
AA12	IO139RSB2
AA13	IO133RSB2
AA14	NC

4-90 Revision 27

FG484	
Pin Number	AGL1000 Function
R9	VCCIB2
R10	VCCIB2
R11	IO147RSB2
R12	IO136RSB2
R13	VCCIB2
R14	VCCIB2
R15	VMV2
R16	IO110NDB1
R17	GDB1/IO112PPB1
R18	GDC1/IO111PDB1
R19	IO107NDB1
R20	VCC
R21	IO104NDB1
R22	IO105PDB1
T1	IO198PDB3
T2	IO198NDB3
Т3	NC
T4	IO194PPB3
T5	IO192PPB3
T6	GEC1/IO190PPB3
T7	IO192NPB3
Т8	GNDQ
Т9	GEA2/IO187RSB2
T10	IO161RSB2
T11	IO155RSB2
T12	IO141RSB2
T13	IO129RSB2
T14	IO124RSB2
T15	GNDQ
T16	IO110PDB1
T17	VJTAG
T18	GDC0/IO111NDB1
T19	GDA1/IO113PDB1
T20	NC
T21	IO108PDB1
T22	IO105NDB1

4-100 Revision 27

FG484		
Pin Number	AGL1000 Function	
Y7	IO174RSB2	
Y8	VCC	
Y9	VCC	
Y10	IO154RSB2	
Y11	IO148RSB2	
Y12	IO140RSB2	
Y13	NC	
Y14	VCC	
Y15	VCC	
Y16	NC	
Y17	NC	
Y18	GND	
Y19	NC	
Y20	NC	
Y21	NC	
Y22	VCCIB1	



IGLOO Low Power Flash FPGAs

Revision	Changes	Page
Revision 19	The following sentence was removed from the "Advanced Architecture" section:	1-3
(continued)	"In addition, extensive on-chip programming circuitry allows for rapid, single-voltage (3.3 V) programming of IGLOO devices via an IEEE 1532 JTAG interface" (SAR 28756).	
	The "Specifying I/O States During Programming" section is new (SAR 21281).	1-8
	Values for VCCPLL at 1.2 V −1.5 V DC core supply voltage were revised in Table 2-2 • Recommended Operating Conditions 1 (SAR 22356).	2-2
	The value for VPUMP operation was changed from "0 to 3.45 V" to "0 to 3.6 V" (SAR 25220).	
	The value for VCCPLL 1.5 V DC core supply voltage was changed from "1.4 to 1.6 V" to "1.425 to 1.575 V" (SAR 26551).	
	The notes in the table were renumbered in order of their appearance in the table (SAR 21869).	
	The temperature used in EQ 2 was revised from 110°C to 100°C for consistency with the limits given in Table 2-2 • Recommended Operating Conditions 1. The resulting maximum power allowed is thus 1.28 W. Formerly it was 1.71 W (SAR 26259).	2-6
	Values for CS196, CS281, and QN132 packages were added to Table 2-5 • Package Thermal Resistivities (SARs 26228, 32301).	2-6
	Table 2-6 • Temperature and Voltage Derating Factors for Timing Delays (normalized to TJ = 70° C, VCC = 1.425 V) and Table 2-7 • Temperature and Voltage Derating Factors for Timing Delays (normalized to TJ = 70° C, VCC = 1.14 V) were updated to remove the column for -20° C and shift the data over to correct columns (SAR 23041).	2-7
	The tables in the "Quiescent Supply Current" section were updated with revised notes on IDD (SAR 24112). Table 2-8 • Power Supply State per Mode is new.	2-7
	The formulas in the table notes for Table 2-41 • I/O Weak Pull-Up/Pull-Down Resistances were corrected (SAR 21348).	2-37
	The row for 110°C was removed from Table 2-45 • Duration of Short Circuit Event before Failure. The example in the associated paragraph was changed from 110°C to 100°C. Table 2-46 • I/O Input Rise Time, Fall Time, and Related I/O Reliability1 was revised to change 110° to 100°C. (SAR 26259).	2-40
	The notes regarding drive strength in the "Summary of I/O Timing Characteristics -	2-28,
	Default I/O Software Settings" section, "3.3 V LVCMOS Wide Range" section and "1.2 V LVCMOS Wide Range" section tables were revised for clarification. They now state that the minimum drive strength for the default software configuration when run in wide range is $\pm 100~\mu A$. The drive strength displayed in software is supported in normal range only. For a detailed I/V curve, refer to the IBIS models (SAR 25700).	2-47, 2-77
	The following sentence was deleted from the "2.5 V LVCMOS" section (SAR 24916): "It uses a 5 V-tolerant input buffer and push-pull output buffer."	2-56
	The values for $F_{DDRIMAX}$ and F_{DDOMAX} were updated in the tables in the "Input DDR Module" section and "Output DDR Module" section (SAR 23919).	2-94, 2-97
	The following notes were removed from Table 2-147 • Minimum and Maximum DC Input and Output Levels (SAR 29428): ±5%	2-81
	Differential input voltage = ±350 mV	
	Table 2-189 • IGLOO CCC/PLL Specification and Table 2-190 • IGLOO CCC/PLL Specification were updated. A note was added to both tables indicating that when the CCC/PLL core is generated by Mircosemi core generator software, not all delay values of the specified delay increments are available (SAR 25705).	2-115



IGLOO Low Power Flash FPGAs

Revision / Version	Changes	Page
DC & Switching, cont'd.	Table 2-49 · Minimum and Maximum DC Input and Output Levels for LVCMOS 3.3 V Wide Range is new.	2-39
Revision 9 (Jul 2008) Product Brief v1.1 DC and Switching Characteristics Advance v0.3	As a result of the Libero IDE v8.4 release, Actel now offers a wide range of core voltage support. The document was updated to change 1.2 V / 1.5 V to 1.2 V to 1.5 V.	N/A
Revision 8 (Jun 2008)	As a result of the Libero IDE v8.4 release, Actel now offers a wide range of core voltage support. The document was updated to change 1.2 V / 1.5 V to 1.5 V.	N/A
DC and Switching Characteristics Advance v0.2	Tables have been updated to reflect default values in the software. The default I/O capacitance is 5 pF. Tables have been updated to include the LVCMOS 1.2 V I/O set. DDR Tables have two additional data points added to reflect both edges for Input DDR setup and hold time. The power data table has been updated to match SmartPower data rather then simulation values.	N/A
	AGL015 global clock delays have been added.	
	Table 2-1 • Absolute Maximum Ratings was updated to combine the VCCI and VMV parameters in one row. The word "output" from the parameter description for VCCI and VMV, and table note 3 was added.	2-1
	Table 2-2 • Recommended Operating Conditions 1 was updated to add references to tables notes 4, 6, 7, and 8. VMV was added to the VCCI parameter row, and table note 9 was added.	2-2
	In Table 2-3 • Flash Programming Limits – Retention, Storage, and Operating Temperature1, the maximum operating junction temperature was changed from 110° to 100°.	2-3
	VMV was removed from Table 2-4 • Overshoot and Undershoot Limits 1. The table title was modified to remove "as measured on quiet I/Os." Table note 2 was revised to remove "estimated SSO density over cycles." Table note 3 was revised to remove "refers only to overshoot/undershoot limits for simultaneous switching I/Os."	2-3
	The "PLL Behavior at Brownout Condition" section is new.	2-4
	Figure 2-2 • V2 Devices – I/O State as a Function of VCCI and VCC Voltage Levels is new.	2-5
	EQ 2 was updated. The temperature was changed to 100°C, and therefore the end result changed.	2-6
	The table notes for Table 2-9 • Quiescent Supply Current (IDD) Characteristics, IGLOO Flash*Freeze Mode*, Table 2-10 • Quiescent Supply Current (IDD) Characteristics, IGLOO Sleep Mode*, and Table 2-11 • Quiescent Supply Current (IDD) Characteristics, IGLOO Shutdown Mode were updated to remove VMV and include PDC6 and PDC7. VCCI and VJTAG were removed from the statement about IDD in the table note for Table 2-11 • Quiescent Supply Current (IDD) Characteristics, IGLOO Shutdown Mode.	2-7
	Note 2 of Table 2-12 • Quiescent Supply Current (IDD), No IGLOO Flash*Freeze Mode1 was updated to include VCCPLL. Note 4 was updated to include PDC6 and PDC7.	2-9



Datasheet Information

Revision / Version	Changes	Page
Advance v0.7 (continued)	The former Table 2-16 • Maximum I/O Frequency for Single-Ended and Differential I/Os in All Banks in IGLOO Devices (maximum drive strength and high slew selected) was removed.	N/A
	The "During Flash*Freeze Mode" section was updated to include information about the output of the I/O to the FPGA core.	2-57
	Table 2-31 • Flash*Freeze Pin Location in IGLOO Family Packages (device-independent) was updated to add UC81 and CS281. Flash*Freeze pins were assigned for CS81, CS121, and CS196.	2-61
	Figure 2-40 • Flash*Freeze Mode Type 2 - Timing Diagram was updated to modify the LSICC Signal.	2-55
	Information regarding calculation of the quiescent supply current was added to the "Quiescent Supply Current" section.	3-6
	Table 3-8 • Quiescent Supply Current (I _{DD}) Characteristics, IGLOO Flash*Freeze Mode [†] was updated.	3-6
	Table 3-9 • Quiescent Supply Current (I_{DD}) Characteristics, IGLOO Sleep Mode (VCC = 0 V) [†] was updated.	3-6
	Table 3-11 • Quiescent Supply Current (I _{DD}), No IGLOO Flash*Freeze Mode1 was updated.	3-7
	Table 3-115 • Minimum and Maximum DC Input and Output Levels was updated.	3-58
	Table 3-156 • JTAG 1532 was updated and Table 3-155 • JTAG 1532 is new.	3-104
	The "121-Pin CSP" and "281-Pin CSP" packages are new.	4-5, 4-7
	The "81-Pin CSP" table for the AGL030 device was updated to change the G6 pin function to IO44RSB1 and the JG pin function to IO45RSB1.	4-4
	The "121-Pin CSP" table for the AGL060 device is new.	4-6
	The "256-Pin FBGA" table for the AGL1000 device is new.	4-34
	The "281-Pin CSP" table for the AGL 600 device is new.	4-8
	The "100-Pin VQFP" table for the AGL060 device is new.	4-18
	The "144-Pin FBGA" table for the AGL250 device is new.	4-24
	The "144-Pin FBGA" table for the AGL1000 device is new.	4-28
	The "484-Pin FBGA" table for the AGL600 device is new.	4-38
	The "484-Pin FBGA" table for the AGL1000 device is new.	4-43
Advance v0.6 (November 2007)	Table 1 • IGLOO Product Family, the "I/Os Per Package1" table, and the "IGLOO Ordering Information", and the Temperature Grade Offerings table were updated to add the UC81 package.	i, ii, iii, iv
	The "81-Pin µCSP" table for the AGL030 device is new.	4-3
	The "81-Pin CSP" table for the AGL030 device is new.	4-1
Advance v0.5 (September 2007)	Table 1 • IGLOO Product Family was updated for AGL030 in the Package Pins section to change CS181 to CS81.	i

5-11 Revision 27